

## IN THE SPECIFICATION

Please replace the paragraph beginning on page 4, line 17, with the following rewritten paragraph.

FIG. 5 confirms that the gate-gray level differences of the sub-defect and the false defect are greater than the gate-gray level difference of the bridge defect that is the killer defect generated during the NVM fabricating process. Therefore, when the threshold value is exemplarily preset as about 30 for detecting the bridge defect, the sub-defect and the false defect are also detected with the bridge defect. Therefore, the bridge defect is not separated from the sub-defect and the false defect.